M5M5256DFP,VP-55LL,-70LL,-70LLI, -55XL,-70XL

262144-BIT (32768-WORD BY 8-BIT) CMOS STATIC RAM

DESCRIPTION

The M5M5256DFP,VP is 262,144-bit CMOS static RAMs organized as 32,768-words by 8-bits which is fabricated using high-performance 3 polysilicon CMOS technology. The use of resistive load NMOS cells and CMOS periphery results in a high density and low power static RAM. Stand-by current is small enough for battery back-up application. It is ideal for the memory systems which require simple interface.

Especially the M5M5256DVP are packaged in a 28-pin thin small outline package.

FEATURE

	Access	Oprating	Power supply current			
Ty pe	time (max)	Temperature	Activ e (max)	Stand-by (max)		
M5M5256DFP,VP-55LL M5M5256DFP,VP-70LL	55ns 70ns	0~70°C		20µA (Vcc=5.5V)		
M5M5256DFP,VP-70LLI	70ns	-40~85°C	50mA (Vcc=5.5V)	40µA (Vcc=5.5V)		
M5M5256DFP,VP-55XL M5M5256DFP,VP-70XL	55ns 70ns	0~70°C		5μA (Vcc=5.5V) 0.05μA (Vcc=3.0V, Typical)		

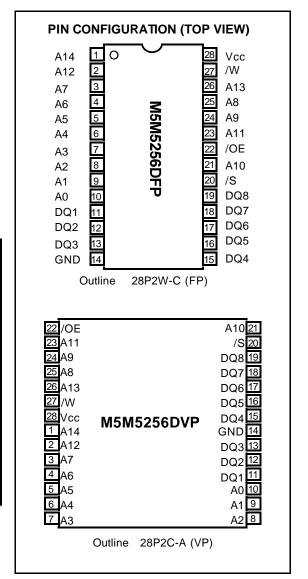
- •Single +5V power supply
- •No clocks, no refresh
- •Data-Hold on +2.0V power supply
- •Directly TTL compatible : all inputs and outputs
- •Three-state outputs : OR-tie capability
- •/OE prevents data contention in the I/O bus
- •Common Data I/O
- •Battery backup capability
- •Low stand-by current $0.05\mu A(ty\,p.)$

PACKAGE

M5M5256DFP : 28 pin 450 mil SOP M5M5256DVP : 28pin 8 X 13.4 mm² TSOP

APPLICATION

Small capacity memory units





RENESAS LSIs

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FUNCTION

The operation mode of the M5M5256DFP,VP is determined by a combination of the device control inputs /S, /W and /OE. Each mode is summarized in the function table

A write cycle is executed whenever the low level /W overlaps with the low level /S. The address must be set up before the write cycle and must be stable during the entire cycle. The data is latched into a cell on the trailing edge of /W, /S, whichever occurs first, requiring the setup and hold time relative to these edge to be maintained. The output enable /OE directly controls the output stage. Setting the /OE at a high level,the output stage is in a high-impedance state, and the data bus contention problem in the write cycle is eliminated.

A read cycle is executed by setting /W at a high level and /OE at a low level while /S are in an active state.

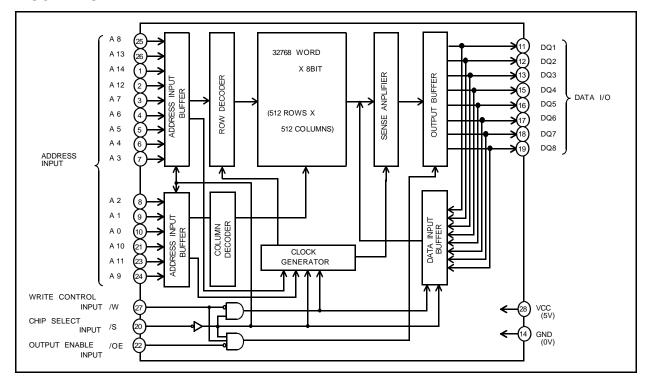
When setting /S at a high level, the chip is in a non-selectable mode in which both reading and writing are disabled. In this mode, the output stage is in a high-impedance state, allowing OR-tie with other chips and memory expansion by /S. The power supply current is reduced as low as the stand-by current which is specified as lcc3 or lcc4, and the memory data can be held at +2V power supply, enabling battery back-up operation during power failure or power-down operation in the non-selected mode.

FUNCTION TABLE

/S	/W	/OE	Mode	DQ	Icc
Н	Х	Х	Non selection	High-impedance	Stand-by
L	L	Х	Write	Din	Activ e
L	Н	L	Read	Dоит	Activ e
L	Н	Н		High-impedance	Activ e

Note • "H" and "L" in this table mean VIH and VIL, respectively.

BLOCK DIAGRAM





^{• &}quot;X" in this table should be "H" or "L".

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ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings	Unit
Vcc	Supply voltage		-0.3*~7.0	V
Vı	Input voltage	With respect to GND	-0.3*~Vcc+0.3 (Max 7.0)	V
Vo	Output voltage		0~Vcc	V
Pd	Power dissipation	Ta=25°C	700	mW
Topr	Operating temperature	-LL,-XL	0~70	00
I opr	Operating temperature	-LLI	-40~85	°C
Tstg	Storage temperature		-65~150	°C

^{* -3.0}V in case of AC (Pulse width < 30ns)

DC ELECTRICAL CHARACTERISTICS (Vcc=5V±10%, unless otherwise noted)

C	Danamatan	Test conditions			Limits			
Symbol	Parameter	i est condi	tions		Min	Тур	Max	Unit
V_{IH}	High-level input voltage				2.2		Vcc +0.3	V
VIL	Low-level input voltage				-0.3*		0.8	V
V _{OH1}	High-level output voltage 1	Iон=-1mA			2.4			V
V _{OH2}	High-level output voltage 2	Iон=-0.1mA			Vcc -0.5			V
VoL	Low-level output voltage	loL=2mA					0.4	V
lı .	Input current	V _I =0~Vcc					±1	μΑ
lo	Output current in off-state	/S=VIH or or /OE=VIH,	/S=Vih or or /OE=Vih, Vi/o=0~Vcc				±1	μΑ
	Icc1 Active supply current (AC, MOS level)	/S≤0.2V,	55ns		30	45		
Icc1		Other inputs<0.2V or >Vcc-0.2V 70ns Output-open 1MHz				25	40	mA
						2	4	
		/S=V _{IL} , 55ns other inputs=V _{IH} or V _{IL} 70ns Output-open 1MHz				30	50	mA
lcc2	Active supply current (AC, TTL level)					25	45	
	(**************************************					4	8	
			~25°C	-LL,-LLI			2	
			~25 C	-XL		0.1	0.4	
		/C: \/aa 0 0\/	~40°C	-LL,-LLI			6	
Icc3	Stand-by current	/S>Vcc-0.2V, other inputs=0~Vcc	~40 C	-XL			1.2	μΑ
		other inputs=0~vcc	~70°C	-LL,-LLI			20	
		1	~10 0	-XL			5	
		~85°C		-LLI			40	
Icc4	Stand-by current	/S=V _{IH} ,other inputs=0	~Vcc				3	mA

^{* -3.0}V in case of AC (Pulse width < 30ns)

CAPACITANCE (Vcc=5V±10%, unless otherwise noted)

	_ ,		Limits		11	
Symbol	Parameter	Test conditions	Min	Тур	Max	Unit
Сі	Input capacitance	V ₁ =GND, V ₁ =25mVrms, f=1MHz			6	pF
Со	Output capacitance	Vo=GND,Vo=25mVrms, f=1MHz			8	pF

Note 0: Direction for current flowing into an IC is positive (no mark).

- 1: Typical value is one at $Ta = 25^{\circ}C$.
- 2: C₁, C₀ are periodically sampled and are not 100% tested.



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$\textbf{AC ELECTRICAL CHARACTERISTICS} \quad (\ \texttt{Vcc=5V\pm10\%}, \ \ \text{unless otherwise noted} \)$

(1) READ CYCLE

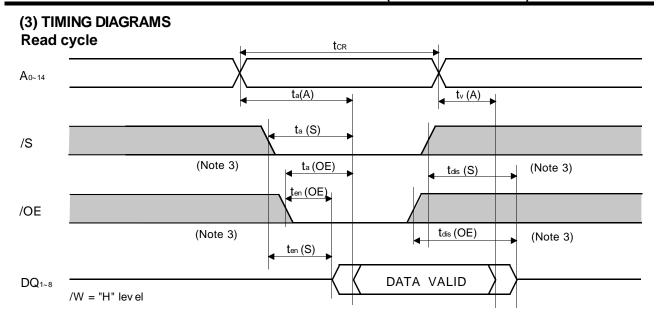
			Limits			
Symbol	Parameter	-55LL	, 55XL		-70LLI, XL	Unit
		Min	Max	Min	Max	•
tcr	Read cycle time	55		70		ns
ta(A)	Address access time		55		70	ns
ta(S)	Chip select access time		55		70	ns
ta(OE)	Output enable access time		30		35	ns
tdis(S)	Output disable time after /S high		20		25	ns
tdis(OE)	Output disable time after /OE high		20		25	ns
ten(S)	Output enable time after /S low	5		5		ns
ten(OE)	Output enable time after /OE low	5		5		ns
t∨(A)	Data valid time after address	10		10		ns

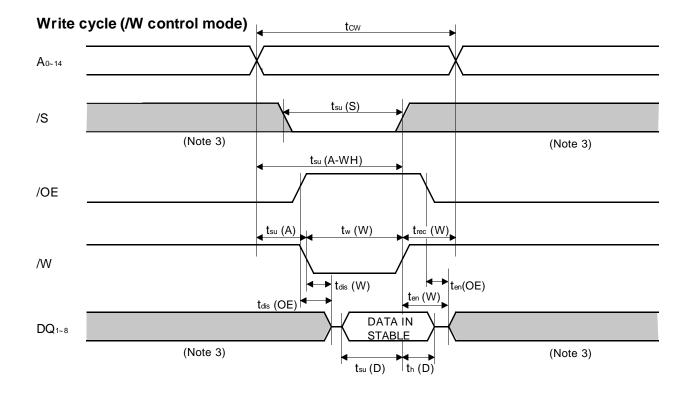
(2) WRITE CYCLE

	Parameter		Limits					
Oa.la a.l			EEVI	-70LL,-70LLI,		Unit		
Symbol			-55LL, -55XL		-70 XL			
		Min	Max	Min	Max			
tcw	Write cycle time	55		70		ns		
t _w (W)	Write pulse width	40		50		ns		
tsu(A)	Address setup time	0		0		ns		
tsu(A-WH)	Address setup time with respect to /W high	50		65		ns		
tsu(S)	Chip select setup time	50		65		ns		
tsu(D)	Data setup time	25		30		ns		
t _h (D)	Data hold time	0		0		ns		
t _{rec} (W)	Write recovery time	0		0		ns		
tdis(W)	Output disable time from /W low		20		25	ns		
tdis(OE)	Output disable time from /OE high		20		25	ns		
ten(W)	Output enable time from /W high	5		5		ns		
ten(OE)	Output enable time from /OE low	5		5		ns		



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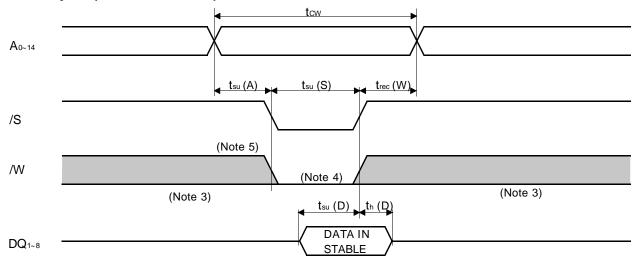




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Write cycle (/S control mode)



Note 3: Hatching indicates the state is "don't care".

4: Writing is executed in overlap of /S and /W low.

5: If /W goes low simultaneously with or prior to /S, the outputs remain in the high impedance state.

6: Don't apply inverted phase signal externally when DQ pin is output mode.

7: ten, tdis are periodically sampled and are not 100% tested.

(4) MEASUREMENT CONDITIONS

Input pulse level $V_{IH}=2.4V, V_{IL}=0.6V$

Input rise and fall time 5ns

Reference level VoH=VoL=1.5V

Output load Fig.1 CL=50pF (-55LL,-55XL)

CL=100pF (-70LL,-70LLI,-70XL)

CL=5pF (for ten,tdis)

Transition is measured ±500mV from steady

state voltage. (for ten,tdis)

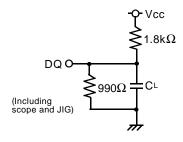


Fig.1 Output load



M5M5256DFP,VP-55LL,-70LL,-70LLI, -55XL,-70XL 262144-BIT (32768-WORD BY 8-BIT) CMOS STATIC RAM

POWER DOWN CHARACTERISTICS

(1) ELECTRICAL CHARACTERISTICS (Vcc=5V±10%, unless otherwise noted)

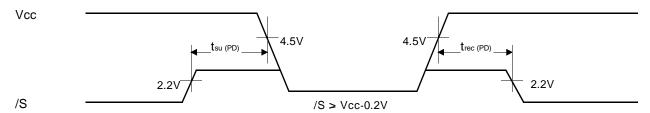
0	Б.,	- .	T		Limits			
Symbol	Parameter	l est co	onditions	3	Min	Тур	Max	Unit
Vcc (PD)	Power down supply voltage			2			V	
		2.2V ≤ VCC(PD)			2.2			V
VI (/S)	Chip select input /S	2V≤ Vcc(PD) ≤ 2	.2V			VCC(PD)		V
	Power down supply current	Vcc = 3V,/S > Vcc-0.2V, Other inputs=0~Vcc	~25°C	-LL,-LLI			1	
				-XL		0.05	0.2	
			~40°C	-LL,-LLI			3	
ICC (PD)				-XL			0.6	μA
				-LL,-LLI			10	
			~70°C	-XL			2	
			~85°C	-LLI			20	

(2) TIMING REQUIREMENTS (Vcc=5V±10%, unless otherwise noted)

0 1 1				Limits				
Symbol	Parameter	Test conditions	Min	Тур	Max	Unit		
tsu (PD)	Power down set up time		0			ns		
trec (PD)	Power down recovery time		tCR			ns		

(3) POWER DOWN CHARACTERISTICS

/S control mode





RENESAS LSIs

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